

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	5005	differential and active and load and semiconductor and test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/27 12:32
L3	11	differential near active near load	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/27 12:39
L4	826	differential adj load	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/27 12:39
L5	165	differential adj load and diode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/27 12:48
L6	136	differential adj load and diode	US-PGPUB; USPAT; USOCR	OR	ON	2005/05/27 12:48